

FCC ID: 2BFVZ-CRYSTALSUPER

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW})/(\text{min. test separation distance, mm})] \cdot \sqrt{f(\text{GHz})} \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- $f(\text{GHz})$ is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BLE:

| Modulation | Channel Freq. (GHz) | Conduct ed power (dBm) | Conducte d power (mW) | Tune-up power (dBm) | Max tune-up power (dBm) | Max tune-up power (mW) | Distance (mm) | Result calculation | SAR Exclusion threshold | SAR test exclusion |
|------------|---------------------|------------------------|-----------------------|---------------------|-------------------------|------------------------|---------------|--------------------|-------------------------|--------------------|
| BLE(1M) | 2.402 | -5.35 | 0.29 | -5±1 | -4 | 0.40 | <5 | 0.12340 | 3.00 | YES |
| | 2.440 | -5.27 | 0.30 | -5±1 | -4 | 0.40 | <5 | 0.12437 | 3.00 | YES |
| | 2.480 | -5.04 | 0.31 | -5±1 | -4 | 0.40 | <5 | 0.12539 | 3.00 | YES |
| BLE(2M) | 2.402 | -5.33 | 0.29 | -5±1 | -4 | 0.40 | <5 | 0.12340 | 3.00 | YES |
| | 2.440 | -5.26 | 0.30 | -5±1 | -4 | 0.40 | <5 | 0.12437 | 3.00 | YES |
| | 2.480 | -5.01 | 0.32 | -5±1 | -4 | 0.40 | <5 | 0.12539 | 3.00 | YES |

Conclusion:

For the max result : $0.12539 \leq 3.0$ for 1g SAR, SAR is not required.

Signature:



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